

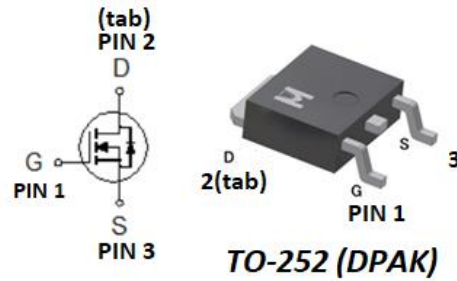
N-Channel Logic Level Enhancement Mode Field Effect Transistor

Product Summary:

BV_{DSS}	100V
$R_{DS(on)} (MAX.)$	12m Ω
I_D	68A

UIS, Rg 100% Tested

Pb-Free Lead Plating & Halogen Free



ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNIT
Gate-Source Voltage		V_{GS}	± 20	V
Continuous Drain Current	$T_C = 25^\circ\text{C}$	I_D	68	A
	$T_C = 100^\circ\text{C}$		43	
Pulsed Drain Current ¹		I_{DM}	150	
Avalanche Current		I_{AS}	18	
Avalanche Energy	$L = 0.1\text{mH}$, $I_D = 18\text{A}$, $R_G = 25\Omega$	E_{AS}	16.2	mJ
Repetitive Avalanche Energy ²	$L = 0.05\text{mH}$	E_{AR}	8.1	
Power Dissipation	$T_C = 25^\circ\text{C}$	P_D	89	W
	$T_C = 100^\circ\text{C}$		35	
Operating Junction & Storage Temperature Range		T_J, T_{stg}	-55 to 150	$^\circ\text{C}$

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNIT
Junction-to-Case	$R_{\theta JC}$		1.4	$^\circ\text{C} / \text{W}$
Junction-to-Ambient	$R_{\theta JA}$		62.5	

¹Pulse width limited by maximum junction temperature.

²Duty cycle $\leq 1\%$

ELECTRICAL CHARACTERISTICS ($T_J = 25\text{ }^{\circ}\text{C}$, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	100			V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu A$	1.0	2.0	3.0	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0V, V_{GS} = \pm 12V$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 80V, V_{GS} = 0V$			1	μA
		$V_{DS} = 70V, V_{GS} = 0V, T_J = 125\text{ }^{\circ}C$			25	
On-State Drain Current ¹	$I_{D(ON)}$	$V_{DS} = 5V, V_{GS} = 10V$	68			A
Drain-Source On-State Resistance ¹	$R_{DS(ON)}$	$V_{GS} = 10V, I_D = 12A$		9.5	12	m Ω
		$V_{GS} = 4.5V, I_D = 10A$		11.5	15	
Forward Transconductance ¹	g_{fs}	$V_{DS} = 5V, I_D = 12A$		45		S
DYNAMIC						
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = 50V, f = 1MHz$		2130		pF
Output Capacitance	C_{oss}			336		
Reverse Transfer Capacitance	C_{rss}			29		
Gate Resistance	R_g	$V_{GS} = 15mV, V_{DS} = 0V, f = 1MHz$		1.5		Ω
Total Gate Charge ^{1,2}	$Q_g(V_{GS}=10V)$	$V_{DS} = 50V, V_{GS} = 10V,$ $I_D = 12A$		38		nC
	$Q_g(V_{GS}=4.5V)$			23		
Gate-Source Charge ^{1,2}	Q_{gs}			10		
Gate-Drain Charge ^{1,2}	Q_{gd}			8.2		
Turn-On Delay Time ^{1,2}	$t_{d(on)}$	$V_{DS} = 50V,$ $I_D = 12A, V_{GS} = 10V, R_{GS} = 6\Omega$		6		nS
Rise Time ^{1,2}	t_r			10		
Turn-Off Delay Time ^{1,2}	$t_{d(off)}$			8		
Fall Time ^{1,2}	t_f			25		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (T _C = 25 °C)						
Continuous Current	I_S				68	A
Pulsed Current ³	I_{SM}				150	
Forward Voltage ¹	V_{SD}	$I_F = 12A, V_{GS} = 0V$			1.2	V
Reverse Recovery Time	t_{rr}	$I_F = 12A, dI_F/dt = 100A / \mu S$		30		nS
Reverse Recovery Charge	Q_{rr}			130		nC



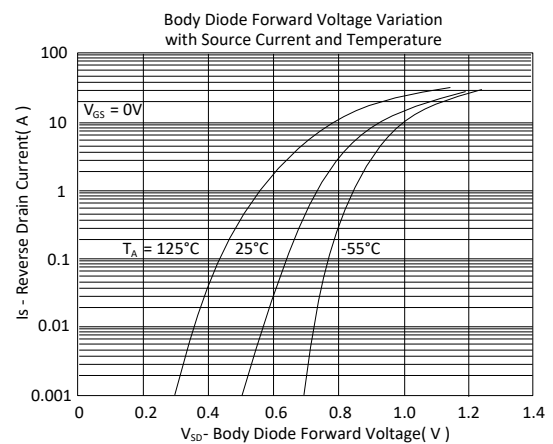
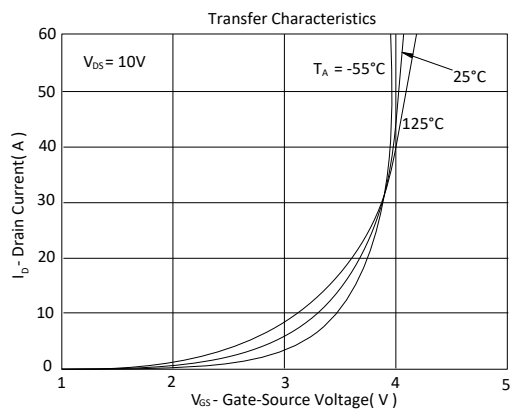
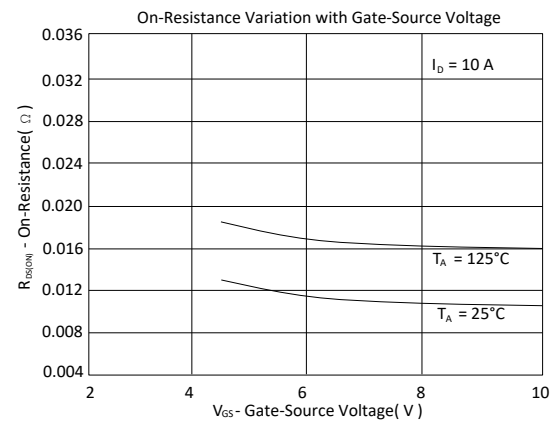
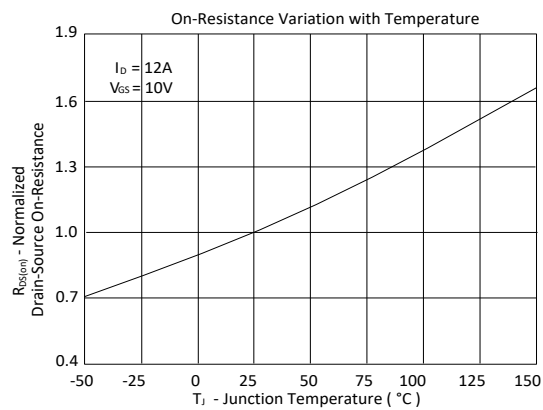
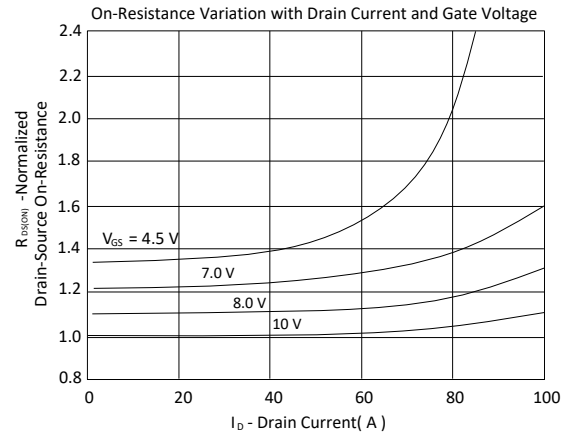
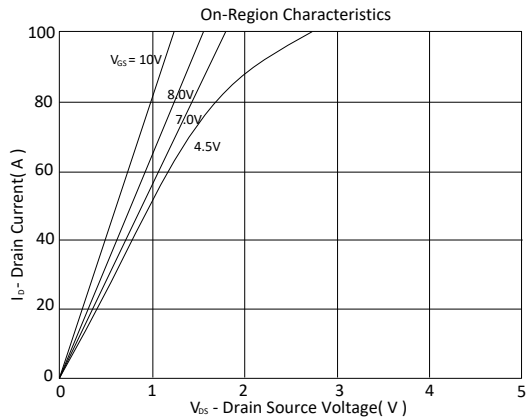
¹Pulse test : Pulse Width $\leq 300 \mu\text{sec}$, Duty Cycle $\leq 2\%$.

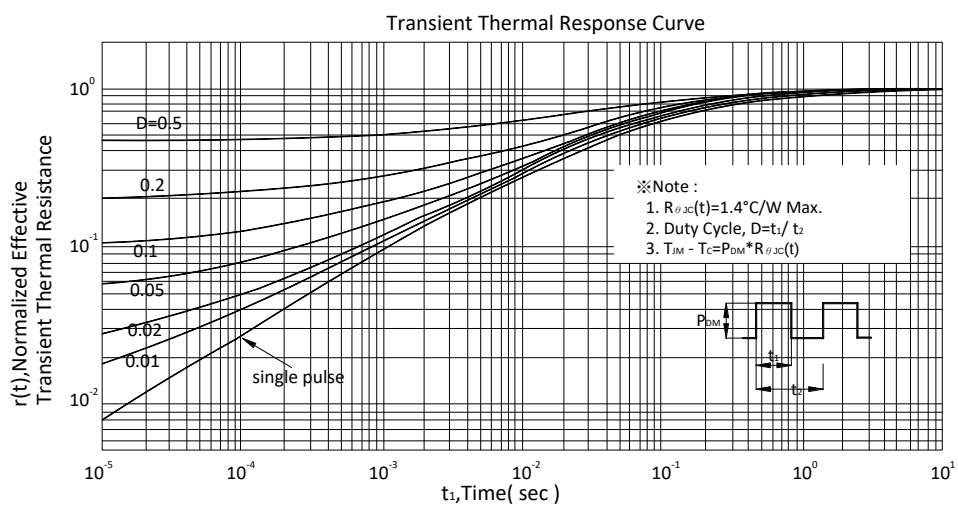
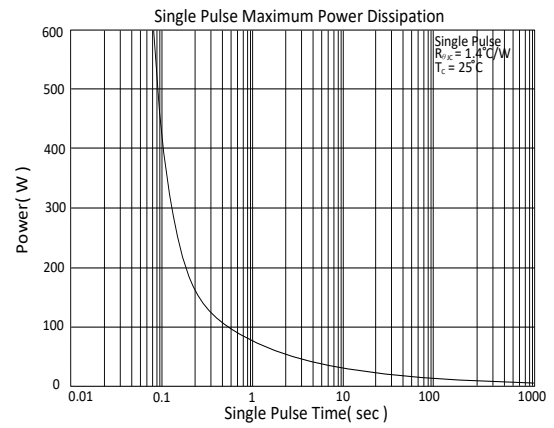
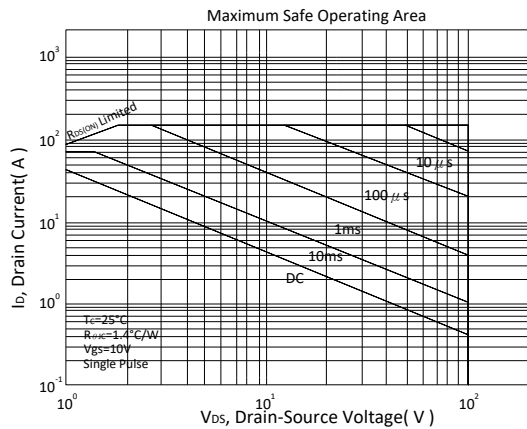
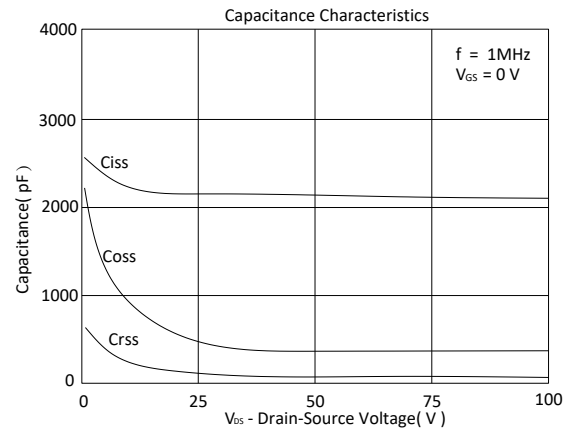
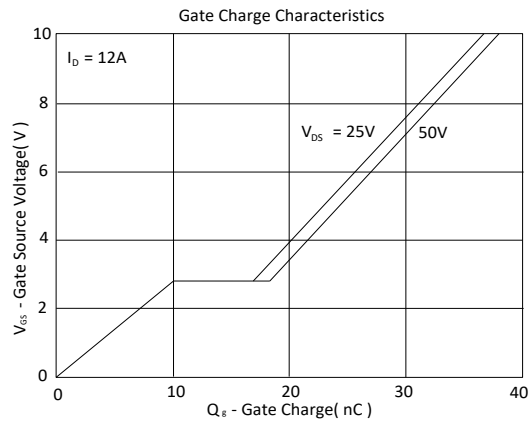
²Independent of operating temperature.

³Pulse width limited by maximum junction temperature.



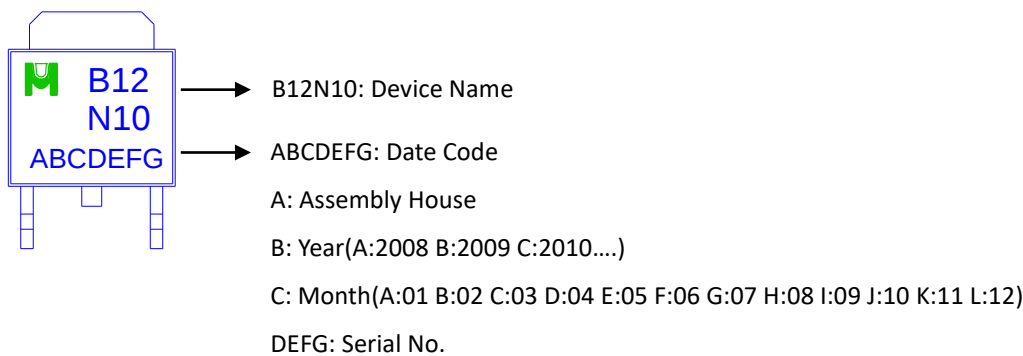
TYPICAL CHARACTERISTICS



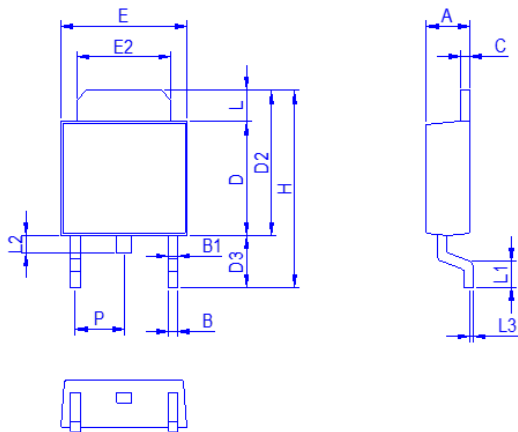


Ordering & Marking Information:

Device Name: EMB12N10A for TO-252 [DPAK]

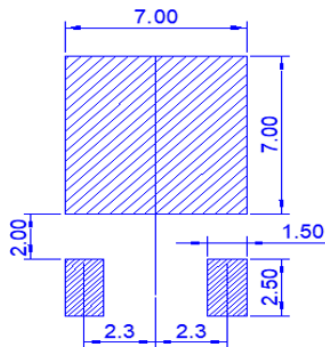


Outline Drawing

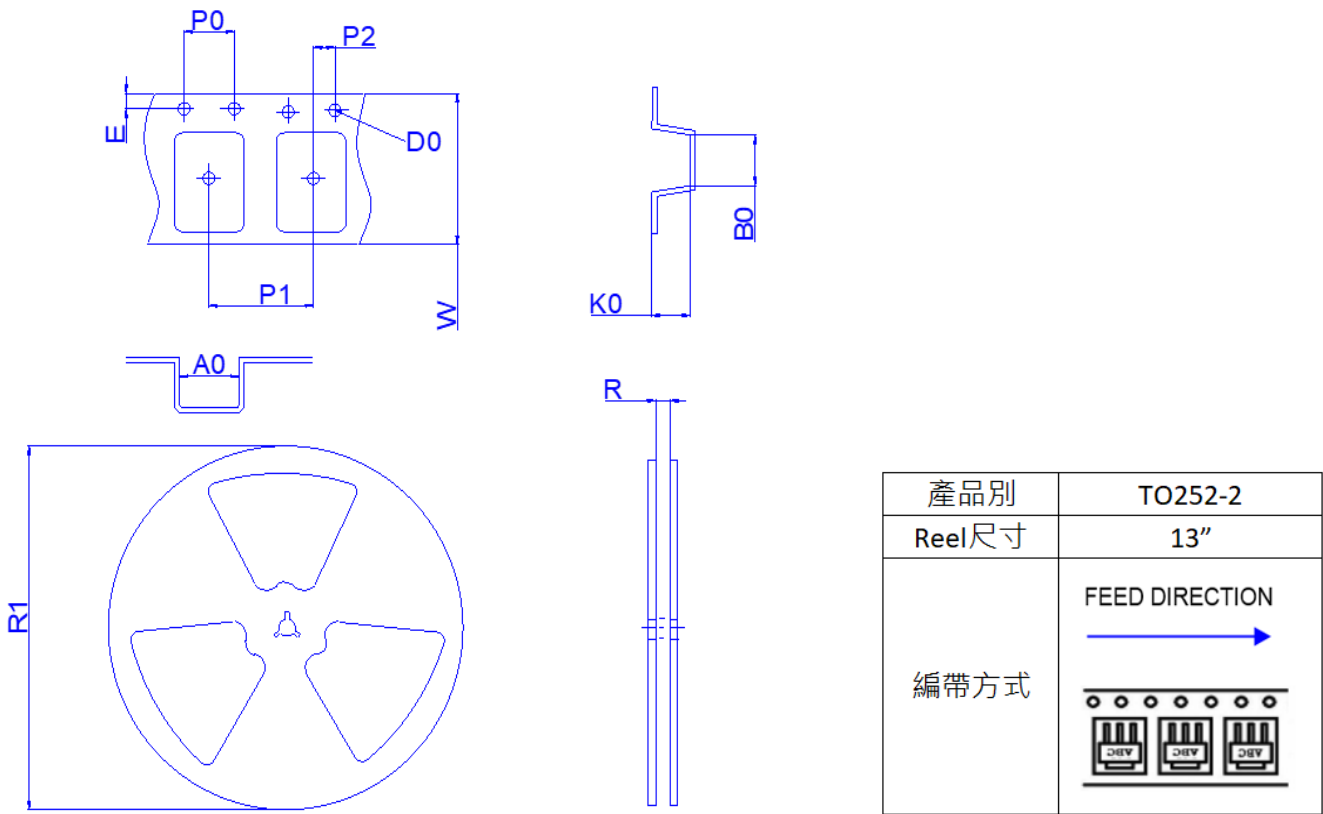


Dimension	A	B	B1	C	D	D2	D3	E	E2	H	L	L1	L2	L3	P
Min.	2.1	0.62	0.65	0.45	5.96	6.8	2.6	6.3	4.9	9.3	0.8	1.2	0.5	0	2.1
Typ.	2.25	0.76	0.9	0.67	6.1	7.15	2.8	6.5	5.2	9.9	1.1	1.65	0.8	0.1	2.25
Max.	2.4	0.9	1.15	0.89	6.24	7.5	3	6.7	5.5	10.5	1.4	2.1	1.1	0.2	2.4

Footprint



Tape&Reel Information:2500pcs/Reel



Dimension in mm

Dimension	Carrier tape									Reel	
	A0	B0	D0	E	K0	P0	P1	P2	W	R	R1
Typ.	6.9	10.5	1.55	1.75	2.7	4	8	2	16	17	330
±	1	1	0.2	0.1	0.2	0.2	0.1	0.1	0.3	2	2